

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Multiple sheets used when necessary)</i>	Application No.	10/815,905
	Filing Date	March 31, 2004
	First Named Inventor	Lin et al.
	Art Unit	2874
SHEET 1 OF 2		Examiner Hoang Q. Tran
		Attorney Docket No. QCO.094A/061113

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Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
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	2	5,312,512	5/17/1994	Allman et al.	
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	25	2004-0100594	5/27/2004	Huibers et al.	

Examiner Signature

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\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T <sup>1</sup>
	26	CH 680534	9/15/1992	Landis & GYR Betriebs AG		X-abstract
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	29	WO 03/046508	6/5/2003	Biomicroarrays		
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NON PATENT LITERATURE DOCUMENTS			
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Examiner Signature /Hoang Tran/ (01/20/2009)	Date Considered
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